ICI E450 L-EFT

Pulse E-Field Source

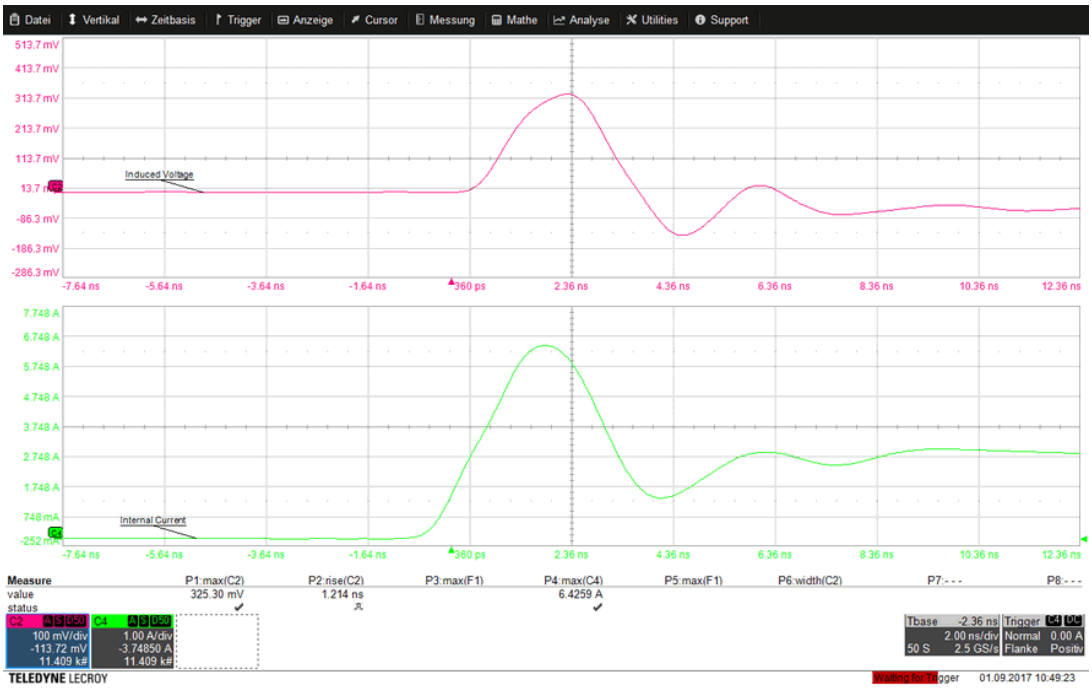
Short description

The ICI E450 L-EFT pulse electric field source couples fast transient pulses into a test IC (open die). This allows for fault injection attacks or testing the immunity of individual areas of the IC.

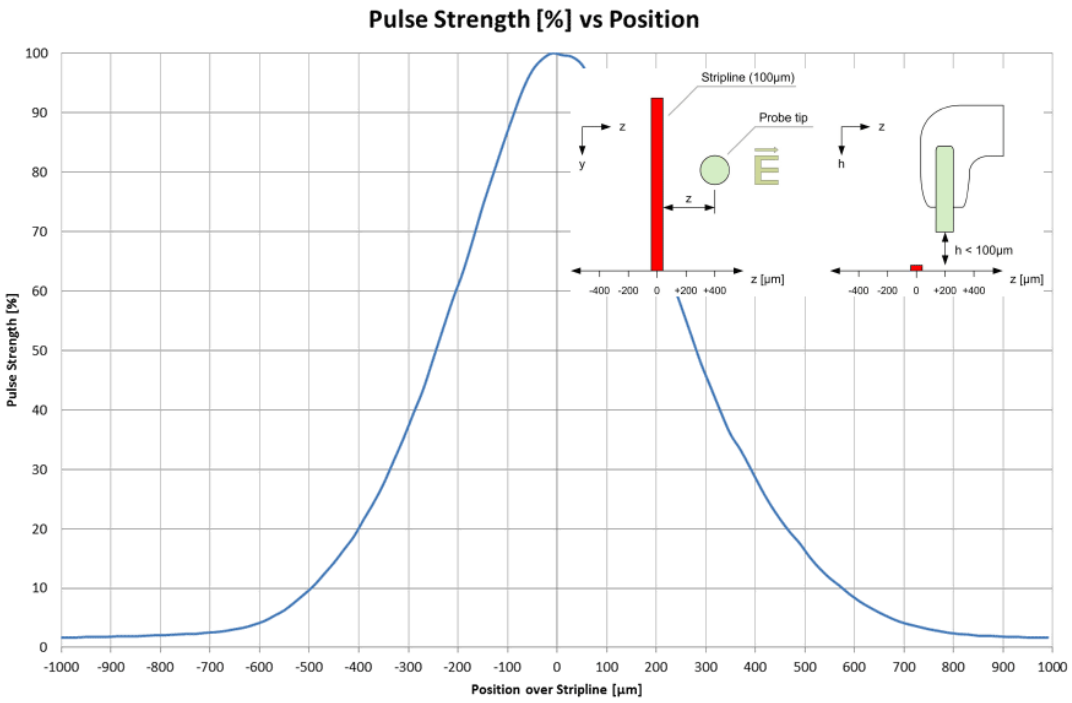
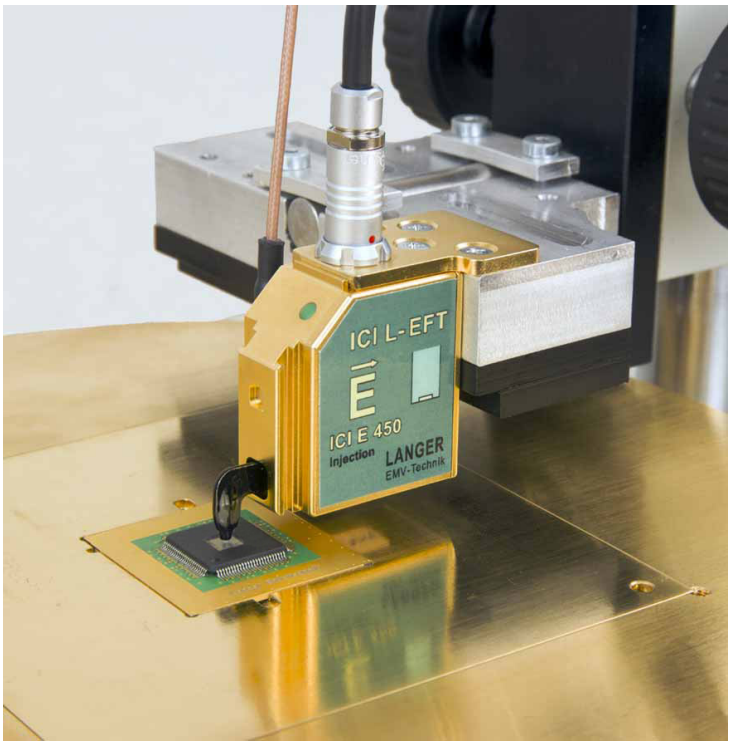
Technical parameters

Probe head dimensions:	Ø 450 µm
Max. Displacement Current (Stripline 100 µm)	7 mA
Pulse parameter	
Rise time	< 2 ns
Repetition frequency	0.1 Hz - 20 kHz
Polarity (set by software)	+ / - / alternating
Measuring output	50 Ω
Trigger-pulse delay (Bypass Mode - Delay Line)	
min. Trigger-pulse delay (typ.)	70 ns
max. Trigger-pulse delay (typ.)	420 ns
max. Jitter (typ.)	± 1 ns
Supply voltage	BPS 202
Weight	70 g
Sizes (L x W x H)	(26 x 43 x 53) mm

Pulse shape



Transverse scan



Application of ICI E450 L-EFT pulse E-field source